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| Notice of References Cited | Application/Control No. 09/973,798 | Applicant(s)/Patent Under Reexamination TAGAWA ET AL. | |
| | Examiner Joseph T Phan | Art Unit 2645 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------|----------------|
| | A | US-5,974,333 | 10-1999 | Chen, Tonny | 455/569.2 |
| | B | US-6,495,747 | 12-2002 | Shimaya et al. | 84/477R |
| | C | US-6,023,700 | 02-2000 | Owens et al. | 707/10 |
| | D | US-6,192,340 | 02-2001 | Abecassis, Max | 704/270 |
| | E | US-2002/0068610 | 06-2002 | Anvekar et al. | 455/560 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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